

Perturbing effects of the probe support on the calibration of electric field meters

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An error occurred in Figure 2, page 347 of the original article.
The correct Figure 2 is as below. We apologise for this error.

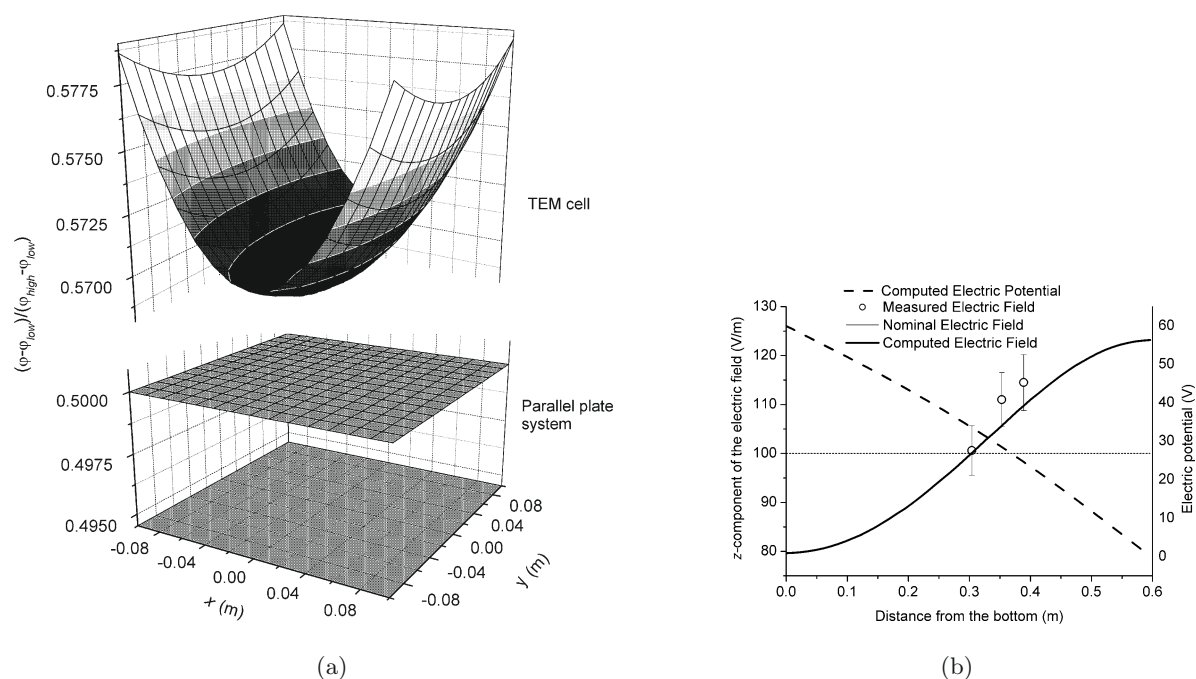


Fig. 2. Normalized electric potential distribution over a square surface around the system center in the parallel plates and in the TEM cell (a). Potential and electric field distribution along a line between the electrodes in the center of the TEM cell (b). The nominal electric field value is 100 V/m; the dots are the measured field values.